

Search Notes

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Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

BARKAN, YUVAL

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	3/28/2007	CH
455	449	3/28/2007	CH

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	3/28/2007	CH
Combined Text Search	3/28/2007	CH
backward/Forward citations of pertinent Art	3/28/2007	CH